

FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20425B

Generic Copy

Issue Date: 08-Nov-2014

<u>TITLE</u>: Final Notification of SOD-123 package/devices qualification for assembly & test in Leshan, China

PROPOSED FIRST SHIP DATE: 08-Feb-2015

AFFECTED CHANGE CATEGORY(S): Assembly and test site

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION: Contact your local ON Semiconductor Sales Office or < jian.peng@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or <MohdAzizi.Azman@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

ON Semiconductor is notifying customers of the qualification and transfer of SOD-123 package assembly and test site from Seremban facility to Leshan facility.

The Leshan facility is certified with ISO/TS 16949:2009 and is currently running production for SOD-123.

The bill of materials used in the SOD-123 package will remain the same between both ON Semiconductor's Seremban and Leshan's facilities.

Reliability qualification and full electrical characterization over temperature has been performed to ensure device functionality and electrical specifications are met.

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RELIABILITY DATA SUMMARY:

Qual Vehicles: Cu Wire

MMSZ5270BT1G				
Test:	Conditions:	Interval:	Results	
Autoclave	Ta=121C, RH=100%, ~15psig	96 hrs	0/240	
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/240	
H3TRB+PC	Ta=85 C RH=85%	1008 hrs	0/240	
	bias=80% rated V or100V Max			
HTSL	Ta=150C	1512 hrs	0/240	
IOL	Ta=25C, delta TJ = 100C			
	Ton=Toff = 2min	15000 cyc	0/240	
TempCycle	Ta= -65/150C	2000 cyc	0/240	
RSH	Ta=260C, 10 sec, elec test		0/90	
Solderability	1a = 245C, 10 sec		0/45	
DPA	per AEC Q101 post IC 1K cyc		0/6	
DPA	per AEC Q101 post H31RB 1008 hr	S	0/6	
MBR0540T1C				
Test:	<u>conditions</u>	Interval [.]	Results	
Autoclave	Ta=121C RH=100% ~15psig	96 hrs	0/160	
HTRB	Ta=90C 80% Rated Voltage	1008 hrs	0/160	
H3TRB+PC	Ta=85 C RH=85%	1008 hrs	0/160	
	bias=80% rated V or100V Max		•••••	
HTSL	Ta=150C	1512 hrs	0/160	
IOL	Ta=25C, delta TJ = 100C			
	Ton=Toff = 2min	15000 cyc	0/160	
TempCycle	Ta= -65/150C	2000 cyc	0/160	
RSH	Ta=260C, 10 sec, elec test		0/60	
Solderabiltiy	Ta = 245C, 10 sec		0/30	
DPA	per AEC Q101 post TC 1K cyc		0/4	
DPA	per AEC Q101 post H3TRB 1008 hr	S	0/4	
MBR130T1G				
lest:		Interval:	Results	
Autoclave	Ta=121C, RH=100%, ~15psig	96 hrs	0/84	
HIRB	Ta=90C,80% Rated Voltage	1008 hrs	0/84	
H31KB+PC	1a=85 C RH=85%	1008 hrs	0/84	
		1510 hrs	0/04	
HISL	13=1500	1512 nrs	0/84	
IOL	Ta=25C, delta $TJ = 100C$	15000 010	0/04	
TompCyclo	1011 = 1011 = 211111	15000 Cyc	0/84	
Гепроусе	$T_{2} = -2600 + 10 \text{ sec}$ also test		0/04	
Soldorabiltiv	$T_2 = 2450^{\circ}$, 10 sec, electrest		0/30	
	ra = 2400, 10 500		0/10	
	per ΔEC 0101 post IC IN 090 ner ΔEC 0101 post H3TRR 1008 br	.e	0/2	
	PELALO QIVI PUSLIBIAD 1000 III	3	0/2	

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BAT54T1G			
Test:	Conditions:	Interval:	Results
	Ta=121C, RH=100%, ~15psig	90 Nrs	0/240
	Ta-150C,00% Rated Voltage	1000 IIIS 1008 brs	0/240
	hias=80% rated V or100V Max	1000 1115	0/240
HTSI		1512 hrs	0/240
IOL	Ta=25C. delta $TJ = 100C$	10121110	0/210
	Ton=Toff = $2min$	15000 cvc	0/240
TempCycle	Ta= -65/150C	2000 cyc	0/240
RSH	Ta=260C, 10 sec, elec test	-	0/90
Solderabiltiy	Ta = 245C, 10 sec		0/45
DPA	per AEC Q101 post TC 1K cyc		0/6
DPA	per AEC Q101 post H3TRB 1008 hrs	;	0/6
MMSD103T1	G		
Test:	<u>Conditions:</u>	Interval:	Results
Autoclave	Ta=121C, RH=100%, ~15psig	96 hrs	0/240
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/240
H3TRB+PC	Ta=85 C RH=85%	1008 hrs	0/240
	bias=80% rated V or100V Max		
HTSL	Ta=150C	1512 hrs	0/240
IOL	Ta=25C, delta TJ = 100C		
	Ton=Toff = 2min	15000 cyc	0/240
TempCycle	Ta= -65/150C	2000 cyc	0/240
RSH	Ta=260C, 10 sec, elec test		0/90
Solderability	1a = 245C, 10 sec		0/45
	per AEC Q101 post 1C TK cyc		0/6
DPA	per AEC QTOT post HSTRB 1000 his	•	0/0
MMSZ9V1T1	G		
Test:	Conditions:	Interval:	Results
Autoclave	Ta=121C, RH=100%, ~15psig	96 hrs	0/240
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/240
H3TRB+PC	Ta=85 C RH=85%	1008 hrs	0/240
	bias=80% rated V or100V Max		
HTSL	Ta=150C	1512 hrs	0/240
IOL	Ta=25C, delta TJ = 100C		
Tama Orala	I on = I off = 2min	15000 cyc	0/240
	1a = -65/150C	2000 cyc	0/240
ROM	$1a-2000$, $10 \sec$, electest		0/90
	1a = 2430, $10 Sec$		0/45
	per AEC Q101 post USTDD 1000 hrs		0/0
			0/0

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Qual Vehicles: Au Wire

SZMMSZ5270BT1G

Test:	Conditions:	Interval:	Results
Autoclave	Ta=121C, RH=100%, ~15psig	96 hrs	0/240
HTRB	Ta=150C,80% Rated Voltage	1008 hrs	0/240
H3TRB+PC	Ta=85 C RH=85%	1008 hrs	0/240
	bias=80% rated V or100V Max		
HTSL	Ta=150C	1008 hrs	0/240
IOL	Ta=25C, delta TJ = 100C		
	Ton=Toff = 2min	15000 cyc	0/240
TempCycle	Ta= -65/150C	1000 cyc	0/240
RSH	Ta=260C, 10 sec, elec test	-	0/90
Solderabiltiy	Ta = 245C, 10 sec		0/45
DPA	per AEC Q101 post TC 1K cyc		0/6
DPA	per AEC Q101 post H3TRB 1008 hrs		0/6

NSI45030AT1G

Test:	Conditions:	Interval:	Results
Autoclave	Ta=121C, RH=100%, ~15psig	96 hrs	0/160
HTOL	Tj=150C,VDS=7.5V	1008 hrs	0/160
HTSL	Ta=150C	1008 hrs	0/160
TempCycle	Ta= -65/150C	1000 cyc	0/160
RSH	Ta=260C, 10 sec, elec test		0/60
Solderabiltiy	Ta = 245C, 10 sec		0/30
DPA	per AEC Q101 post TC 1K cyc		0/4
DPA	per AEC Q101 post H3TRB 1008 hrs		0/4

ELECTRICAL CHARACTERISTIC SUMMARY:

Available upon request

CHANGED PART IDENTIFICATION:

Affected products from ON semiconductor with date code 1502 representing WW02, 2015 and greater may be sourced from either the Seremban factory or the Leshan factory.

List of affected General Parts:

MMSZ4714T1G